Certificate of Analysis

IARM 205D

AISI 422 / UNS S42200

Certified Reference Material

Certified Values listed in wt.% with associated uncertainties

Al	**0.0021** ± 0.0006	**As**	**0.004** ± 0.001	**B**	**0.0007** ± 0.0003	**C**	**0.232** ± 0.002
Co	**0.043** ± 0.002	**Cr**	**12.18** ± 0.03	**Cu**	**0.122** ± 0.002	**Mn**	**0.736** ± 0.006
Mo	**1.002** ± 0.009	**N**	**0.0484** ± 0.0007	**Nb**	**0.013** ± 0.001	**Ni**	**0.841** ± 0.008
O	**0.0053** ± 0.0004	**P**	**0.0209** ± 0.0007	**Pb**	**0.002** ± 0.004	**S**	**0.0028** ± 0.0003
Si	**0.257** ± 0.005	**Sn**	**0.0047** ± 0.0004	**Ti**	**0.0022** ± 0.0006	**V**	**0.319** ± 0.004
W	**1.07** ± 0.02	**Zr**	**0.0022** ± 0.0007				

Indicative Values listed in ppm

Ca (20)	Ce (<10)	Mg (7)	Sb (<70)	Se (<50)	Ta (<50)	Zn (<50)

Description and Intended Use

This CRM may come in the form of a solid disc or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

Interpretation of Data

1. Certified values listed reflect analysis results submitted by qualified analytical laboratories using a combination of methods and instrumentation that emulate actual methods and instrumental techniques currently utilized in the analytical community, and are reported as wt% unless otherwise noted.
2. This material was tested using both the solid disks and chips prepared from individual sections of bar. The certified values are considered representative of the overall average composition of the material.
3. Any data reported and enclosed by a parentheses ( ) is a "best estimate" and is not certified. This data could not be quantified sufficiently for certification. It was, however, reported by enough laboratories to be considered as potentially present in the matrix of the material being examined.
4. "Provisional Certificate of Analysis" reports values that support a fully certified reference material; it also indicates that values may be in a continued process of statistical evaluation and are subject to change.
5. Chips are not certified for Oxygen analysis.

The following data and accompanying statements represent all pertinent information reported in the ILAP as it applies to the chemical characterization of this material.

	Al	As	B	C	Ca	Ce	Co	Cr	Cu	Mg	Mn	Mo	N	Nb	Ni	O
1	0.00089	0.0019	0.00015	0.2254	0.00076	0.0001	0.038	12.077	0.116	0.0001	0.7205	0.966	0.046	0.0096	0.814	0.0048
2	0.001	0.0034	0.0002	0.228	0.0009		0.0395	12.11	0.117	0.0006	0.723	0.974	0.0468	0.011	0.822	0.0049
3	0.0017	0.0047	0.0004	0.2286	0.00098		0.0395	12.118	0.12	0.0009	0.731	0.983	0.0476	0.0114	0.825	0.0049
4	0.0018	0.0048	0.0006	0.2295	0.0024		0.041	12.13	0.12	<0.0001	0.7326	0.9925	0.048	0.012	0.832	0.0049
5	0.0022	0.0052	0.0006	0.23	<0.003		0.0411	12.14	0.1207		0.733	0.996	0.0485	0.0125	0.8327	0.0053
6	0.00255	0.006	0.0007	0.2327			0.0412	12.17	0.121		0.733	1.00	0.0486	0.0126	0.839	0.0058
7	0.00255		0.0008	0.233			0.04225	12.176	0.121		0.7345	1.0012	0.0486	0.013	0.84	0.0062
8	0.0026		0.0012	0.233			0.043	12.181	0.122		0.736	1.005	0.04865	0.0139	0.842	
9	0.0026		0.0013	0.2338			0.0434	12.20	0.122		0.737	1.01	0.0488	0.014	0.843	
10	0.0029			0.234			0.0443	12.214	0.123		0.739	1.012	0.04895	0.0141	0.8483	
11	0.004			0.2345			0.0447	12.23	0.1232		0.7395	1.015	0.0493	0.0147	0.85	
12				0.239			0.045	12.2301	0.1236		0.75	1.018	0.05	0.0154	0.854	
13							0.0462	12.2595	0.1241		0.75	1.018		0.017	0.8576	
14							0.05	12.299	0.125		0.7604	1.02			0.87	
15									0.128			1.024				
Mean	0.0021	0.004	0.0007	0.232	0.002		0.043	12.18	0.122	0.0007	0.736	1.002	0.0484	0.013	0.841	0.0053
STDV.	0.0009	0.001	0.0004	0.004	0.001		0.003	0.06	0.003	0.0005	0.01	0.02	0.001	0.002	0.01	0.0005
Certified	**0.0021**	**0.004**	**0.0007**	**0.232**	**(0.002)**	**(<0.0001)**	**0.043**	**12.18**	**0.122**	**(0.0007)**	**0.736**	**1.002**	**0.0484**	**0.013**	**0.841**	**0.0053**
95% C.I.	0.0006	0.001	0.0003	0.002			0.002	0.03	0.002		0.006	0.009	0.0007	0.001	0.008	0.0004
Methods	X,O,I,G	O,IM,I,H	O,I,G	O,C	O,I	IM		X,O,I,G	X,O,I,G	X,O,IM,I,H	X,O,I,G	X,O,I,G	O,F	X,O,I,G	X,O,I,G	O,F

	P	Pb	S	Sb	Se	Si	Sn	Ta	Ti	V	W	Zn	Zr			
1	0.0185	0.00003	0.0021	0.0008	0.0002	0.236	0.0033	0.00001	0.001	0.31	1.01	0.0001	0.0011			
2	0.019	0.0001	0.0024	0.001	0.0015	0.24	0.0038	0.0012	0.001	0.312	1.018	0.0001	0.0019			
3	0.019	0.00021	0.0024	0.0019	<0.0001	0.25	0.004	0.003	0.0011	0.314	1.027	0.0005	0.002			
4	0.0206	0.0004	0.0025	0.0021	<0.0001	0.253	0.0043	0.003	0.0015	0.314	1.0545	0.0046	0.0024			
5	0.021	0.0009	0.0025	0.0069	<0.0006	0.2557	0.0047	0.006	0.0018	0.3143	1.055		0.0029			
6	0.021	0.013	0.0026		<0.0020	0.257	0.0048	<0.0001	0.0019	0.316	1.065					
7	0.021		0.00285		<0.005	0.258	0.005	<0.0030	0.0022	0.316	1.0681					
8	0.0211		0.003			0.259	0.005	<0.005	0.0026	0.317	1.08					
9	0.0212		0.003			0.26	0.0052		0.003	0.317	1.08					
10	0.0215		0.0032			0.262	0.0053		0.0035	0.3189	1.082					
11	0.0218		0.0032			0.262	0.0055		0.0036	0.3234	1.09					
12	0.022		0.0039			0.263				0.325	1.099					
13	0.0222					0.2633				0.3286	1.1174					
14	0.0229					0.265				0.33	1.122					
15											1.126					
Mean	0.0209	0.002	0.0028	0.002	0.001	0.257	0.0047	0.002	0.0022	0.319	1.07	0.001	0.0022			
STDV.	0.001	0.005	0.0005	0.002	0.0008	0.009	0.0007	0.002	0.0009	0.007	0.03	0.002	0.0007			
Certified	**0.0209**	**0.002**	**0.0028**	**(<0.007)**	**(<0.005)**	**0.257**	**0.0047**	**(<0.005)**	**0.0022**	**0.319**	**1.07**	**(<0.005)**	**(0.0022)**			
95% C.I.	0.0007	0.004	0.0003			0.005	0.0004		0.0006	0.004	0.02					
Methods	X,O,I,G	X,O,IM,H	O,C	X,O,IM,H	X,O,IM,I,H	X,O,I,G	X,O,IM,I,H	X,O,IM,I	X,O,I,G	X,O,I,G	X,O,I,G	X,IM,I,H	X,O,IM,I			

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

Participating Laboratories

Exova - Burlington	Burlington, ON	AADFW, Inc.	Euless, TX
Crucible Industries	Syracuse, NY	Laboratory Testing, Inc.	Hatfield, PA
LECO Corporation	St. Joseph, MI	SPECTRO Analytical Instruments Inc.	Mahwah, NJ
Anderson Laboratories, Inc.	Greendale, WI	Special Metals IncoTest	Hereford, UK
Laboratorio Prove Materiali S. Marco srl	Schio, Italy	Ellwood National Steel	Irvine, PA
Cronimet Specialty Metals USA, Inc.	Wheatland, PA	AK Steel, Research Center	Middletown, OH

Traceability

Members of the "Inter-Laboratory Analysis Program" (ILAP) validate test methods and instrument performance utilizing SRMs, CRMs, and RMs produced by recognized Certifying Bodies. The specific SRMs, CRMs, and RMs applicable to the material covered by this certificate are:

2Q13S1	2Q13S2	ALPHA AR651	ALPHA AR654	ALPHA AR659	ALPHA AR878	ALPHA AR883	ALPHA AR889	ASTM 0721
BCS 334	BCS 335	BCS 351-1	BCS 462-1	BCS SS422	BCS SS471	BS 152	BS 156	BS 183A
BS 410B	BS 60C	BS 84J	BS 8620B	BS 89C	BS 90C	BS 90F	BS 92B	BS 93E
BS 94C	BS 97	BS 98	BS CSN 2-2	BS SS4951	ECRM 289-1	ECRM 722	IARM 10A	IARM 13C
IARM 154A	IARM 154B	IARM 164A	IARM 16A	IARM 16B	IARM 205A	IARM 205B	IARM 205C	IARM 21B
IARM 238A	IARM 253A	IARM 2B	IARM 2C	IARM 319A	IARM 35J	IARM 4B	IARM 9B	IARM 9C
IH AKS 584	IH AKS 585	IH AKS 598	IH AKS 669	IH AKS598	LECO 501-503	LECO 501-504	LECO 501-553	LECO 501-644
LECO 501-646	LECO 501-991	LECO 501-992	LECO 502-106	LECO 502-328	LECO 502-402	LECO 502-414	LECO 502-416	LECO 502-494
MBH 13X12548M	MBH 13X41001A	MBH 13X81101B	MBH 13XNSA8A	MBH14XHS10A	NIST 1216	NIST 13G	NIST 2166	NIST 293
NIST 3101A	NIST 3107	NIST 3109A	NIST 3110	NIST 3155	NIST 3162A	NIST 339	NIST 361	NIST 363
NIST 73B								

Homogeneity and Uncertainty

"Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity is also determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by equation 2, where $H=U_{hom}$, S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

1. $$N_{min} = \max(10, \sqrt[3]{N_{prod}})$$

2. $$U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$$

The International Standards Organization (ISO) definitions, expressed in ISO Guide 30–1992 list the following:

Certifying Body: Any technically competent body (organization or firm, public or private) that issues a reference material certificate with the information detailed in ISO Guide 31. The only generally accepted certifying body in the United States for primary standards or Standard Reference Materials (SRM) is the U. S. Department of Commerce, National Institute of Standards & Technology (NIST), Gaithersburg, MD. All other certifying bodies in the United States produce Reference Materials (RM) or Certified Reference Materials (CRM).

Reference Material (RM): Material or substance, with one or more property values that are sufficiently homogeneous and well established, to be used for the calibration of an apparatus, the assessment of a measurement method, or for assigning values to materials.

Certified Reference Material (CRM): Reference material, accompanied by a certificate, with one or more property values certified by a procedure, which establishes its traceability to an accurate realization of the unit in which the property values are expressed, and for which each certified value is accompanied by an uncertainty at a stated level of confidence.

Inter-Laboratory Analysis Program (ILAP): ASTM Standard E691-87 applies to inter-laboratory studies to "Determine the Precision of a Single Test Method", but also outlines a well thought out and logical plan for conducting an inter laboratory program involving multiple analytical techniques. Therefore, the guidelines established in ASTM E691-87 were applied to all aspects of this inter laboratory program, including the protocols for planning, handling, analysis and treatment of resulting data.

Methods of Analysis: The "Inter Laboratory Analysis Program" analyzes a wide variety of materials, and as a result, no single analytical method would provide optimum analytical results. Therefore, a combination of ASTM Standard Methods for classical wet chemistry, ICP, AA, Optical Emission, X-Ray spectrometric, and other accepted methods were used to produce analytical data. Carbon, Sulfur, Nitrogen, and Oxygen results were supplied from combustion and OE instrument procedures.

Expiration of Certification: The certification of this IARM is valid indefinitely, within the uncertainty specified, provided the IARM is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the IARM is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

Instructions for Use: The test surface is on the side opposite to the labeled surface, which includes the IARM number. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. Chips are not to be used for Oxygen analysis.

Selection of Materials: A "batch" or "series" is defined as a continuous length of bar produced from a single heat. The majority of IARM materials are in wrought condition; other methods of manufacture are utilized if necessary. ILAP samples are removed from equal sections from the total length of the bar. A portion of each section is converted to chips and a thin (pin) disk for analysis by classical wet chemistry, ICP, AA, and combustion procedures, and the balance remains as a thick disk for OES and X-Ray analysis.

David Coler, General Manager

Analytical Reference Materials International

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